

SimXRD-4M: Big Simulated X-ray Diffraction Data Accelerate the Crystalline Symmetry Classification

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Abstract

Spectroscopic data, particularly diffraction data, contain detailed crystal and microstructure information and thus are crucial for materials discovery. Powder X-ray diffraction (XRD) patterns are greatly effective in identifying crystals. Although machine learning (ML) has significantly advanced the analysis of powder XRD patterns, the progress is hindered by a lack of training data. To address this, we introduce SimXRD, the largest open-source simulated XRD pattern dataset so far, to accelerate the development of crystallographic informatics. SimXRD comprises 4,065,346 simulated powder X-ray diffraction patterns, representing 119,569 distinct crystal structures under 33 simulated conditions that mimic real-world variations. We find that the crystal symmetry inherently follows a long-tailed distribution and evaluate 21 sequence learning models on SimXRD. The results indicate that existing neural networks struggle with low-frequency crystal classifications. The present work highlights the academic significance and the engineering novelty of simulated XRD patterns in this interdisciplinary field. SimXRD aims to advance symmetry identification research and is freely accessible at <http://simxrd.caobin.asia/>.

1 Introduction

Crystals embody a distinct and precisely structured form of matter, constituted by atoms or molecules arranged in long-range order [21]. Symmetry identification is a fundamental and crucial step for materials characterization and design. Specifically, XRD analysis stands out as exceptionally potent for probing microstructure, due to its sensitivity to atomic arrangement and the element specificity of atom scattering power. The diffraction pattern reflects the atomic arrangement of the diffracting material, as depicted in Figure 1. XRD patterns serve as a fingerprint of the crystals, and the identification of symmetry has been a fundamental practice in the decoding process.

The traditional method involves a search-match process [1] among numerous known powder diffraction patterns. Given a target XRD pattern, it iterates candidates in databases until satisfactory

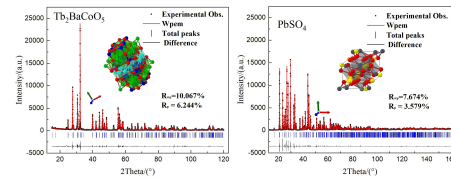


Figure 1: The X-ray diffraction patterns of crystal Tb_2BaCoO_5 and $PbSO_4$.

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alignment is achieved. Although such a method is prevalent, it is time-consuming [1, 34, 19] due to two issues: (1) high dependency on human intervention. Matching processes rely on domain-specific programs. Human-assisted tuning is often required during program execution; (2) diffraction is an intricate multi-physical coupling processes. The complex interplay between scattering signals and the convolution of crystalline peaks poses a challenge to structure analysis. The intensity of each observed peak in the spectrum is influenced by external conditions such as grain size, temperature and instrument, resulting in peak broadening [53] that obscures the precise peak location. This complexity renders pattern symmetry analysis extremely challenging, even for experienced domain experts.

To address the above problems, recent studies [28, 57, 35, 63, 27, 58, 9, 51] train neural networks [31] on simulated XRD datasets. They treat XRD patterns as sequences and aim to classify them to specific symmetry (e.g., crystal systems or space groups). Despite significant progress, several limitations exist in current model development and evaluation:

- **Lack of a large-scale and high-quality dataset:** The ultimate goal of symmetry identification tasks is to develop a general model capable of recognizing symmetry from experimental measurements, emphasizing extensive coverage and high fidelity. Previous research has been largely confined to specific materials[15, 28, 63]. For example, Lee et al. [28] focus on mixtures of 38 distinct binary and ternary crystals in the Sr-Li-Al-O inorganic compounds. Additionally, the geometric similarity of crystals and experimental physical factors can result in XRD patterns with similar peak distributions. Therefore, sufficient coverage of structures and close alignment with experimental patterns under different physical conditions is necessary for developing models with high generalization ability.
- **Insufficient comparison of recurrent and transformer models:** Transformers have shown impressive results in sequence modeling applications such as time series and text classifications. Additionally, recurrent models like Recurrent Neural Networks (RNNs)[52], Long Short-Term Memory (LSTM)[17], and Gated Recurrent Units (GRUs)[8] have long been employed as well. These models can be applied to symmetry identification but a systematic comparison between them and CNNs is still absent.

Crafting such a high-fidelity simulated XRD pattern dataset is challenging due to the many domain-specific simulation processes, such as determining crystal stability, instrumental settings, and physical environments. In this work, we present SimXRD, the largest open-sourced and physically comprehensive dataset aimed at advancing this new interdisciplinary domain. It was developed based on the mature refinement software [4], established by researchers from material science. We use advanced Material Project as a crystal source and filter out crystals of broken symmetry, duplication, or discrepancies in space groups. Consequently, SimXRD comprises 4,065,346 X-ray powder diffraction patterns covering 119,569 distinct crystal structures simulated under various conditions, including grain size, orientation, internal stress, inelastic scattering, thermal vibration, instrumental zero shift, and noise. Through the analysis of SimXRD, we discovered that the symmetry of real-world crystals, as exemplified by the Materials Project (MP) [20] database, follows a long-tail distribution.

Notably, the low-frequency space group is still vital in crystallography. Benchmarking the model performance on such a **long-tailed sequence classification** problem is crucial for the academia-industry need for real-time crystal analysis. Thus, we evaluate the performance on SimXRD of 20 models, which can be divided into three types of sequence models: convolution neural networks (i.e., the backbone of existing symmetry classification models), recurrent models, and transformers.

In summary, our contributions are:

- We introduce SimXRD, the largest open-source simulation dataset for symmetry identification, including 4,065,346 XRD patterns of 119,569 high-quality crystals .
- We highlight the long-tailed distribution in symmetric identification and find that most existing methods achieve low accuracy in space groups of low frequency.
- We construct a comprehensive benchmark of 21 models of three types of sequence models. We integrate SimXRD and all models mentioned in this paper into an open-source repository.

³Union of ICSD and MP database, existing the same structures.

Table 1: Summaries of existing powder XRD datasets. ICSD refers to the commercial Inorganic Crystal Structure Database. MP denotes the open-sourced Material Project.

Dataset	#XRD Pattern	#Structure	Open Access	Simulated	Crystal Source	Year
RRUFF [22]	3,002	3,002	✓	×	-	2015
XRDSP [55]	169,536	169,536	✓	✓	ICSD	2020
CNN [28]	1,785,405	170	×	✓	ICSD	2020
PQNet [14]	250,000	1	✓	✓	ICSD	2021
XRDAutoAnalyzer [57]	38,250	150	✓	✓	ICSD	2021
XRDIAllYouNeed [26]	328,503	189,476&139,027 ³	×	✓	ICSD&MP	2022
AdvancedXRDAalysis [27]	29,569,650	197,131	×	✓	ICSD	2023
CrySTINet [7]	100	100	✓	✓	ICSD	2024
CPICANN [5]	692,190	23,073	✓	✓	COD	2024
SimXRD	4,065,346	119,569	✓	✓	MP	2024

2 Related Work

2.1 Existing datasets

Several datasets have been developed to train neural models for crystallography. Table 1 provides a summary of these datasets, compared along several key dimensions:

- **Dataset Size:** Existing open-source databases either contain relatively small structures tailored to specific purposes [7, 14, 57, 28] or consider limited environmental settings [7, 55]. Crystal structure databases form the backbone of XRD pattern databases. Although the database developed by Lee et al. [26, 27] covers almost all the crystals in the Inorganic Crystal Structure Database (ICSD) [64] or the Materials Project (MP) [20]. A significant number of crystals are repeated and with broken symmetries. SimXRD employs the entire MP database of January 2024, totaling 154,718 crystal structures. During the generation of the SimXRD database, we applied screening methods to improve crystal quality. Additionally, we simulate XRD patterns under various environments to meet the academic-industry requirements.
- **Availability:** Most pattern datasets are openly available, as indicated in Table 1, though some datasets can only be retrieved upon reasonable request [28, 26, 27]. Additionally, published diffraction pattern datasets are saved in various formats, requiring specific data loaders provided by the authors. In contrast, the SimXRD-4M dataset developed in our work is fully available and features an easier workflow for machine learning training, easily integrable with TensorFlow or PyTorch frameworks.
- **Simulation vs. Experiments:** Among the existing datasets, only the RRUFF Project [22] aims to create a comprehensive set of high-quality spectral data from well-characterized minerals. Since its inception in 2005 [50], RRUFF has compiled a collection of 3,002 high-quality experimental powder XRD patterns as of March 2024. However, conducting the experiments is time-consuming. Thus, recent studies have employed domain-specific software to generate simulated data. Rather than relying solely on software like Pymatgen [41] and FullProf [48] to simulate patterns under finite real-world conditions, SimXRD accounts for a broader range of comprehensive real-world conditions. These include grain size, internal stress, external temperature variations, grain orientation, instrument drift, instrument noise, and scattering-induced background.

2.2 Symmetry identification

Existing methods rely on one-dimensional convolutional neural networks for building classification models. Almost all related research originates from the materials community due to the lack of easily accessible datasets. The models developed in recent years have primarily focused on CNN architectures [14, 63, 42]. In particular, they focus on designing CNNs with deep layers [26] and large kernel sizes [23], ensemble CNNs [35, 57], and CNNs without dropout [28] and pooling layers [51]. However, whether CNNs can address long-tailed distributions and the performance of other sequence models are still underexplored.

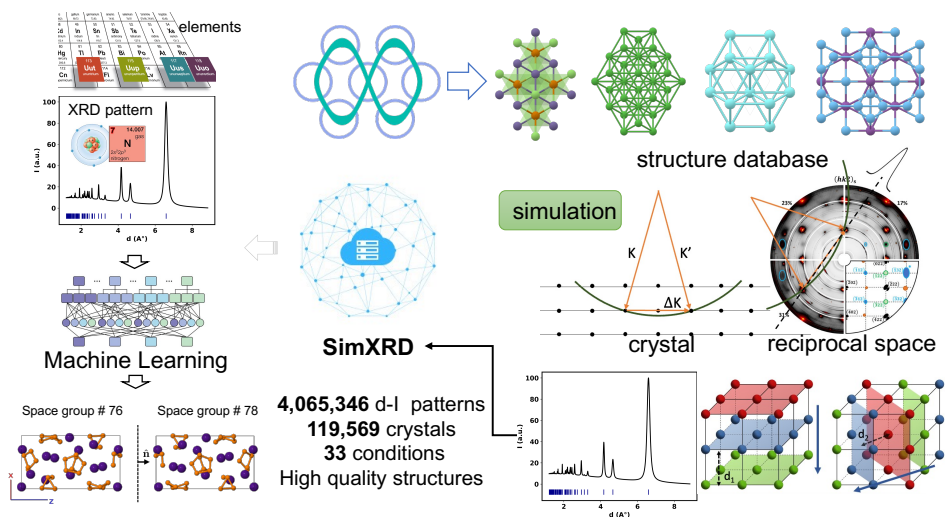


Figure 2: The transformation from crystal structure to XRD pattern, accounting for finite grain size, specific orientation, thermal vibrations, zero shift adjustments, and the scattering background.

3 SimXRd-4M Dataset

In this section, we first introduce the fundamental concepts of the research problem and then elaborate on the dataset construction process and analysis results.

3.1 Preliminaries

Crystal symmetry Symmetry in crystallography is a fundamental property of the orderly arrangements of atoms found in crystalline solids. Each atomic arrangement possesses certain symmetry elements, which are transformations that leave the arrangement unchanged. These elements include rotation, translation, reflection, and inversion. The specific symmetry elements present in a crystalline solid determine its shape and influence its physical properties. Crystals are classified based on their symmetry elements, falling into one of 7 crystal systems, and could further divided into 230 space groups [12].

XRD pattern Powder XRD patterns offer a one-dimensional representation of the three-dimensional diffraction pattern and stand as the most common experimental measurement. Specifically, each one-dimensional powder X-ray diffraction pattern in SimXRd is presented in the format of d-I (lattice plane distance-intensity), where the x-axis is lattice plane distances and the y-axis is corresponding intensities, as shown in Figure 2. Lattice plane distances denote the detected atomic directions. Some distances lack peaks due to geometric constraints from the lattice cell and extinction effects [32] under diffraction. The relative intensity is normalized, with the maximum intensity value set to 100, making the pattern independent of the incident X-ray intensity.

Symmetry classification Formally, SimXRd considers the following multi-class sequence classification problem. Given the XRD pattern $\mathbf{X} = [x_1, x_2, \dots, x_n] \in \mathbb{R}^n$ where x_i is the i -th intensity value and \mathbf{X} is arranged by lattice plane distance, the object is to predict its symmetry $\mathbf{Y} \in \mathbb{R}^k$. Here n is the feature dimension which is 3501 in our dataset. $k = 7$ for crystal system classification and $k = 230$ for space group classification. We did not consider practical factors such as average grain size and stress as input variables, as these are not directly measurable in real-world diffraction experiments.

3.2 Data Generation and Processing

Crystal data The crystal structures utilized in this study were sourced from Material Project [20], a comprehensive, searchable database containing information about solid-state materials and molecules. It provides detailed data on these materials’ physical properties, such as elastic tensors, band structures, and formation energies, derived from electronic structure calculations, offering a more comprehensive reference for crystal studies. We utilize the latest dataset, denoted as MP-2024.1, encompassing a total of 154,718 crystallographic structures of January 2024.

Crystal Filtering To ensure consistency between recorded space group numbers (crystal systems) and atomic arrangements, and to enhance the quality of crystal structures, we conducted a thorough examination of each structure in the MP database. We utilized Spglib [59], a library designed for identifying and managing crystal symmetries, to check all structures. Structures displaying broken symmetry, duplication, or discrepancies in space groups were excluded. Additionally, only structures containing up to 500 atoms per lattice cell were retained, effectively encompassing nearly all inorganic materials in the MP dataset. A total of 119,569 crystal structures were screened.

Simulation in SimXRD Figure 2 illustrates the overall simulation process. The experimental XRD patterns are determined by both the crystal’s intricate structure and practical factors including the state of the specimen and the instrumental parameters. Our goal is to simulate this process via domain-specific custom refinement software WPEM [4]. We first specify environmental settings and then compute the XRD patterns of given crystals. By varying the environmental parameters, we construct all samples of SimXRD. We systematically analyze the physical conditions influencing the XRD profiles, categorized into factors impacting the specimen’s internal structure and those influencing instrumental measurements. These parameters, along with their respective value ranges, are introduced in the Appendix. For each input crystal, we randomly couple these physical conditions within reasonable ranges, repeating the process 33 times to simulate XRD patterns in diverse environments. Each XRD pattern is standardized, with the x-axis values (lattice plane distance) uniformly set based on the experimental settings, resulting in a vector of 3501 dimensions. The y-axis values (diffraction intensity) are simulated according to the crystal structure and diffraction conditions.

Dataset availability The XRD data is stored as standard database (db) files in the Atomic Simulation Environment (ASE). Each row in the database contains a diffraction pattern consisting of 3051 d-I pair values (lattice plane distance (d) and diffraction intensity (I)), along with the chemical formula (string), atomic elements (list), space group (integer), and crystal system (integer). Users can utilize a command-line tool called ‘ase db’ to query and manipulate these databases. Additionally, a Python interface is available, as detailed in the introduction of the SimXRD documentation.

3.3 Data Analysis

We analyze the crystal system and space group distribution to provide insights into building neural network solutions. To investigate the data quality of SimXRD, we plot the formation energy of its crystals, which reflects the stability of structures. A case study between experimental and simulated XRD patterns is displayed to validate our simulation algorithm’s effectiveness.

Long-tailed distribution The distributions of space groups and crystal systems are shown in Figure 3A and B. We can observe that the classes are highly imbalanced and follow a long-tailed distribution. Given that MP-2024.1 serves as a comprehensive database of commonly occurring material systems, this distribution imbalance is inherent to the physical population of crystals in nature. This imbalance can lead to biased model performance as the model may be more inclined to predict the majority class, leading to lower accuracy for the minority classes. Since minority crystal is also important for material discovery, addressing long-tailed sequence learning is crucial for symmetry identification. However, existing models do not consider such a challenge, evaluating their performance in different classes is necessary.

Formation Energy The formation energy (E_f) of a configuration represents the energy required or released to generate that configuration. Thus, the formation process can be either endothermic or exothermic. The more negative the formation energy of a structure, the more stable the structure,

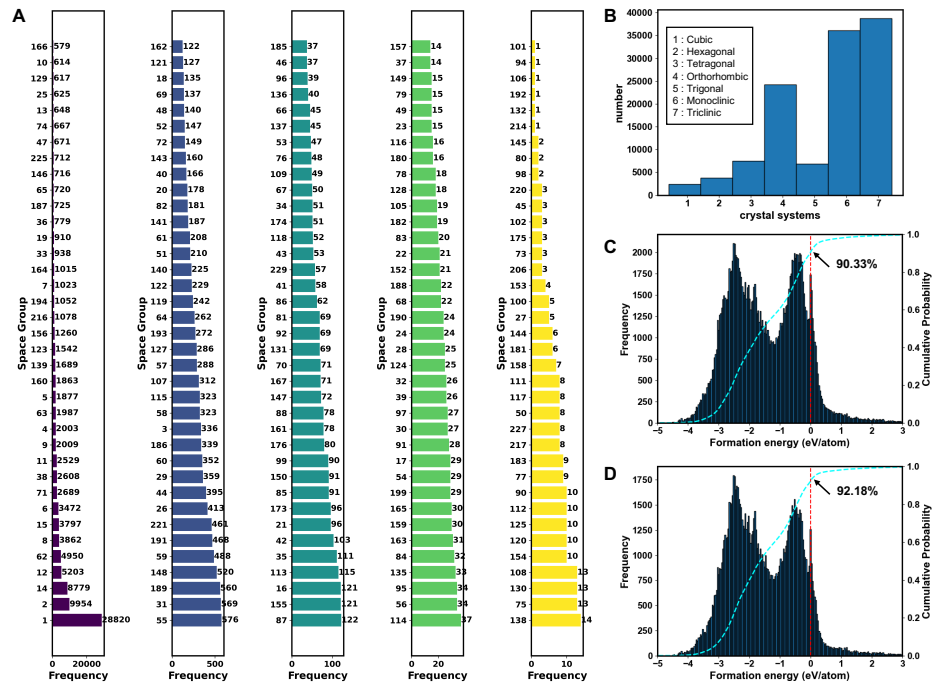


Figure 3: The statics of dataset. (A) The distribution of structures contained in the SimXRD database across various space groups (uniformly divided into 5 categories according to the frequency) and (B) crystal systems (C) The distribution of formation energy/atom of crystals contained in MP-2024.1 and (D) SimXRD. Space groups 89, 103, and 104 have been excluded from Figure A to enhance clarity, each appearing only once.

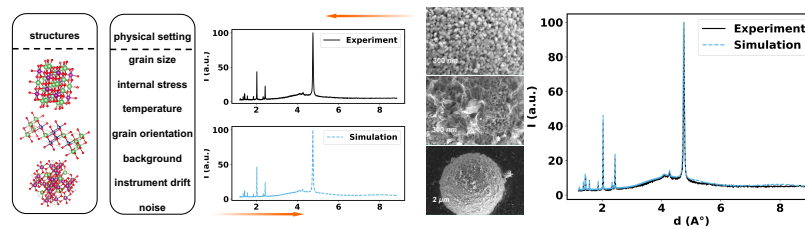


Figure 4: The comparison between experimental measurement patterns and generated XRD patterns using WPDM, based on a Li-rich layered oxide cathode structure with a primary phase of Li_2MnO_3 .

indicating its thermal stability [60]. Figures 3C and D illustrate the formation energy per atom across 154,718 crystal structures in MP-2024.1 and 119,569 crystal structures in SimXRD. Figure 3C highlights the high-quality crystal data in MP-2024.1, with 90.33% of structures exhibiting negative formation energy. Sequentially, the crystal data in SimXRD shows a negative formation energy rate of 92.18%, indicating that the excluded crystals are mainly relatively unstable structures. This high-quality structural data serves as the cornerstone of XRD pattern databases.

Case study A case study is conducted to investigate the difference between experimental and simulated XRD patterns of Li_2MnO_3 . Initially, the physical states of the tested specimens and the experimental settings were obtained using a refinement method (see Appendix). Subsequently, the XRD pattern was generated inversely through the WPDM. Figure 4 shows their results where we can observe that the generated profile exhibits extreme similarity to the experimental measurements[29]. Therefore, by altering the physical states within a reasonable range, other patterns that correspond to different experimental settings can be generated. Such simulation allows us to obtain high-quality data in a relatively efficient way, compared to experimental patterns.

4 Use Cases of SimXRD Dataset

To further demonstrate the practical utility and applicability of SimXRD, we explore its use in two critical tasks: crystal system classification and space group classification. We concentrate on in-library classification, a fundamental task in crystallography, which aims to precisely identify crystal types by analyzing XRD patterns across various physical coupling conditions. Therefore, the dataset is randomly split according to the types of simulated environments, resulting in $119,569 \times 30$ training instances, $119,569 \times 1$ validation instances, and $119,569 \times 2$ testing instances. The data recorded for training, validation, and testing include crystals from different simulated environments (e.g., grain size, stress, temperature).

Baselines We consider the following three types of sequence classification models:

- **CNN-based Models:** We evaluate all existing CNN architectures that are proposed for symmetry identification. Since most of models do not have specific names, we classified them based on their number of convolution layers, pooling layers, and whether they use ensemble learning and dropout layers. Table 2 summarizes the existing 11 CNNs.
- **Recurrent Models:** We select three basic recurrent neural networks: RNN [37], LSTM [17], and GRU [11]. Moreover, since XRD patterns can be viewed from both forward and backward, we also evaluate the bidirectional RNN, LSTM, and GRU performance [52].
- **Transformers:** Transformers have proven effective in diverse sequence modeling tasks. We evaluate the performance of raw transformer [62] and two advanced transformer models - iTransformer [30] and PatchTST [40].

Besides these models, we further add MLP as a straightforward baseline. For recurrent models and transformers, we first use them to learn sequence representations, and then employ an MLP to predict the symmetry.

Implementation details We use the following hyper-parameters across all experiments: Batch size 128, learning rate 2.5×10^{-4} . All models are trained for 50 epochs with an early stopping patience of 3. We use the Cross-Entropy function to measure the loss between prediction and the ground truth. We use accuracy, macro F1-score, macro precision, and macro recall as our metrics to measure the performance of the models. All models are implemented based on the Pytorch [43] library, trained on GeForce RTX 3090 GPU.

Overall performance Table 2 displays the baseline performance and inference time for the classification of crystal systems and space groups. Based on the results, we have the following observations:

- Most existing CNN models are unsuitable for symmetry identification within the large scale of SimXRD database. It is clear that the crystal system classification accuracies of multiple CNNs, e.g., CNN 4 and 6 are on par with that of MLP. The reason, as shown in the next paragraph and Figure 3, is that their predictions are heavily biased by classes of high frequency, thus they can not predict the low-frequency classes. Such weakness is more obvious in space group classification where the accuracy of most CNNs (i.e., CNN 1-4, 6, and 8) is 0.241, indicating their outputs are almost fixed to the most frequent space group.
- Convolutional neural networks without pooling have achieved the best performance in most tasks, consistent with the findings of previous work [51]. Since the peak maximum and the relative value among peaks of XRD patterns are highly related to the atom arrangement of crystals, employing pooling layers may cause information loss, affecting the identification of peaks and leading to lower accuracy.
- Bidirectional recurrent models consistently outperform their unidirectional counterparts. These results reveal an important physical attribute of XRD patterns. That is, ensure the consistent retrieval of crystal information through bidirectional pattern reading. Such property differs from previous sequence tasks such as text and time-series classification, which requires further model designs.
- The raw transformer encounters difficulties when dealing with this long-tailed sequence problem. Nevertheless, compared to it, we can observe that PatchTST achieves significant performance

Table 2: Results of crystal system classification and space group classification. Inference time is measured for a batch size of 100 samples and experiments are run on a GeForce RTX 3090 GPU.

Model #	Conv. #	Dropout #	Pooling #	Ensemble Ref.	Accuracy	F1	Precision	Recall	Time (ms)	Accuracy	F1	Precision	Recall	Time (ms)	
CNN1	3	✓	AvgPool	×	[42]	0.559	0.418	0.427	0.431	3.2	0.241	0.002	0.001	0.005	3.4
CNN2	2	×	MaxPool	×	[28]	0.466	0.236	0.222	0.283	1.8	0.241	0.002	0.001	0.005	1.9
CNN3	3	×	MaxPool	×	[28]	0.531	0.328	0.315	0.369	3.5	0.241	0.002	0.001	0.005	3.6
CNN4	7	✓	MaxPool	×	[63]	0.316	0.069	0.045	0.143	1.4	0.241	0.002	0.001	0.005	1.4
CNN5	3	✓	AvgPool	✓	[35]	0.517	0.394	0.489	0.378	0.6	0.295	0.022	0.025	0.026	0.6
CNN6	7	✓	MaxPool	×	[14]	0.316	0.069	0.045	0.143	65.0	0.241	0.002	0.001	0.005	65.0
CNN7	6	✓	MaxPool	✓	[57]	0.862	0.863	0.887	0.845	6.8	0.588	0.124	0.147	0.130	6.9
CNN8	14	✓	MaxPool	×	[26]	0.377	0.162	0.148	0.221	3.1	0.241	0.002	0.001	0.005	3.1
CNN9	3	✓	MaxPool	×	[23]	0.795	0.817	0.826	0.810	1.9	0.599	0.597	0.681	0.556	1.9
CNN10	4	✓	MaxPool	×	[23]	0.870	0.888	0.892	0.885	1.8	0.705	0.792	0.853	0.759	1.8
CNN11	3	✓	None	×	[51]	0.902	0.922	0.932	0.914	4.8	0.758	0.750	0.735	0.828	4.8
			MLP			0.316	0.069	0.045	0.143	1.6	0.241	0.002	0.001	0.005	1.6
			RNN			0.381	0.183	0.200	0.202	8.0	0.245	0.003	0.002	0.007	8.1
			LSTM			0.728	0.743	0.762	0.728	14.6	0.515	0.156	0.224	0.151	14.6
			GRU			0.765	0.788	0.802	0.777	15.1	0.575	0.273	0.400	0.251	15.1
			Bidirectional-RNN			0.365	0.155	0.197	0.185	14.7	0.245	0.003	0.002	0.007	14.7
			Bidirectional-LSTM			0.791	0.814	0.825	0.805	29.1	0.559	0.384	0.533	0.346	29.1
			Bidirectional-GRU			0.800	0.826	0.840	0.816	30.3	0.627	0.451	0.609	0.408	30.3
			Transformer			0.338	0.127	0.172	0.155	83.4	0.241	0.002	0.001	0.005	83.5
			iTransformer			0.627	0.611	0.652	0.599	1.9	0.388	0.135	0.320	0.118	1.9
			PatchTST			0.720	0.752	0.766	0.740	3.3	0.631	0.811	0.850	0.784	3.3

improvement, demonstrating subsequence-level patches are beneficial to identify peaks and further improve classification performance.

Performance w.r.t. long-tailed distribution To further investigate the model performance, we display the accuracy of each crystal system and space group of different frequencies in Figure 5. To better visualize the model performance on space group, we divided the results of 280 space groups into 5 categories according to their frequency (the same as Figure 3). From the results, we can observe:

- In crystal system classification, the performance of most CNN models, the raw RNN, and transformers is affected by the frequency of crystal systems. They can not predict the XRD patterns of Cubic and Hexagonal symmetry (their accuracies are almost zero). In contrast, multiple domain-specific CNN (i.e., CNN 7, 9, 10, 11), LSTM, GRU, and advanced Transformers (i.e., iTransformer and PatchTST) can mitigate long-tail distributions.
- Space group classification is more challenging than crystal system classification. Most models can only predict space groups with high frequency and hardly predict most low-frequency space groups. Surprisingly, PatchTST achieves comparable performance with the best models in all low-frequency space groups. Given that PatchTST is a model specifically tailored for time series forecasting, its performance on XRD pattern classification has considerable room for improvement.

5 Conclusion

In this paper, we propose SimXRD, the largest open-source XRD pattern dataset for symmetry identification. Through data analysis, we find that the symmetry follows a long-tailed distribution. Our evaluation of 21 models shows that most existing models can not work well in predicting the symmetry of low frequency, limiting their real-world applications. Our results underline the importance of modeling long-tailed sequence classification and comprehensive comparison in accurately understanding the capabilities of various models. We make SimXRD open-source to facilitate further research and improvement of symmetry identification algorithms.

Limitations Although SimXRD enhances prior datasets from multiple perspectives (e.g., sample size, crystal quality, and accessibility), long-tailed and imbalanced label distribution is its inherent limitation. The distribution of crystallographic symmetry arises through natural processes and is invariant to human intervention. Such biases are difficult or even impossible to address in any dataset. Thus, possible solutions are to develop specific class-imbalanced algorithms or employ additional information on target crystals.

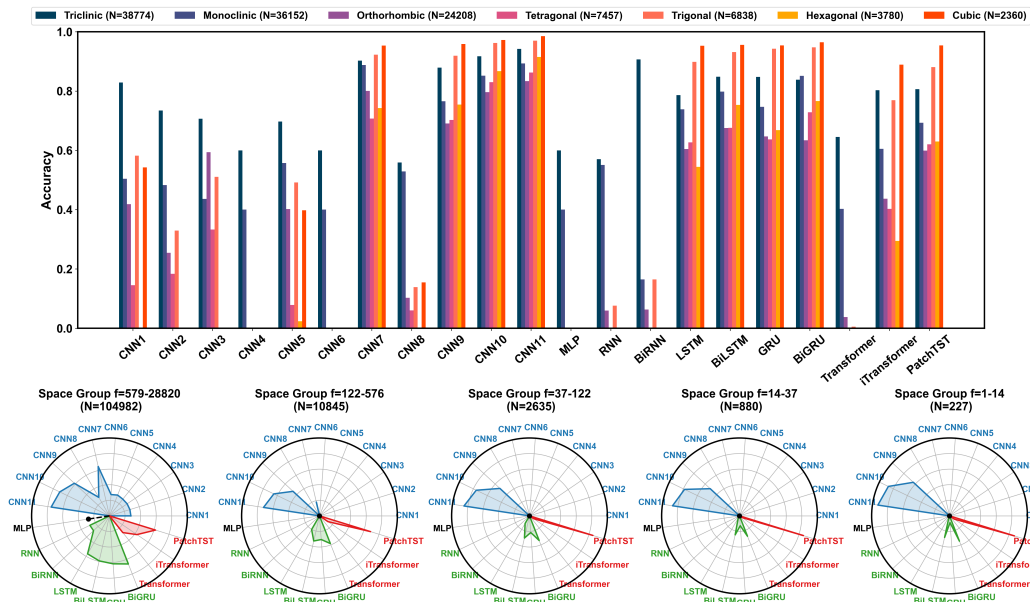


Figure 5: Classification accuracy of each model w.r.t. crystal systems and space groups. The same as Figure 3(A), Space groups are classified into 5 categories based on their frequency. N denotes the number of crystals.

Future works We regard SimXRD as a long-term evolving project and are dedicated to its continuous development. At present, we focus on in-library identification, which is predominant in the materials science community. In the future, we plan to (1) develop long-tailed sequence classification models through data augmentation [10] or enhance features via multi-model inputs; (2) evaluate the out-library symmetry classification performance of existing models.

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Checklist

The checklist follows the references. Please read the checklist guidelines carefully for information on how to answer these questions. For each question, change the default **[TODO]** to **[Yes]**, **[No]**, or **[N/A]**. You are strongly encouraged to include a **justification to your answer**, either by referencing the appropriate section of your paper or providing a brief inline description. For example:

- Did you include the license to the code and datasets? **[Yes]** See Section 2.
- Did you include the license to the code and datasets? **[No]** The code and the data are proprietary.
- Did you include the license to the code and datasets? **[N/A]**

Please do not modify the questions and only use the provided macros for your answers. Note that the Checklist section does not count towards the page limit. In your paper, please delete this instructions block and only keep the Checklist section heading above along with the questions/answers below.

1. For all authors...
 - (a) Do the main claims made in the abstract and introduction accurately reflect the paper's contributions and scope? **[Yes]**
 - (b) Did you describe the limitations of your work? **[Yes]**
 - (c) Did you discuss any potential negative societal impacts of your work? **[No]**
 - (d) Have you read the ethics review guidelines and ensured that your paper conforms to them? **[Yes]**
2. If you are including theoretical results...
 - (a) Did you state the full set of assumptions of all theoretical results? **[N/A]**
 - (b) Did you include complete proofs of all theoretical results? **[N/A]**
3. If you ran experiments (e.g. for benchmarks)...
 - (a) Did you include the code, data, and instructions needed to reproduce the main experimental results (either in the supplemental material or as a URL)? **[Yes]** See Abstract.
 - (b) Did you specify all the training details (e.g., data splits, hyperparameters, how they were chosen)? **[Yes]** See Implementation details.
 - (c) Did you report error bars (e.g., with respect to the random seed after running experiments multiple times)? **[No]**
 - (d) Did you include the total amount of compute and the type of resources used (e.g., type of GPUs, internal cluster, or cloud provider)? **[Yes]**
4. If you are using existing assets (e.g., code, data, models) or curating/releasing new assets...
 - (a) If your work uses existing assets, did you cite the creators? **[Yes]**
 - (b) Did you mention the license of the assets? **[Yes]**
 - (c) Did you include any new assets either in the supplemental material or as a URL? **[Yes]**
 - (d) Did you discuss whether and how consent was obtained from people whose data you're using/curating? **[Yes]**
 - (e) Did you discuss whether the data you are using/curating contains personally identifiable information or offensive content? **[N/A]**
5. If you used crowdsourcing or conducted research with human subjects...
 - (a) Did you include the full text of instructions given to participants and screenshots, if applicable? **[N/A]**
 - (b) Did you describe any potential participant risks, with links to Institutional Review Board (IRB) approvals, if applicable? **[N/A]**
 - (c) Did you include the estimated hourly wage paid to participants and the total amount spent on participant compensation? **[N/A]**

A Appendix

A.1 More details about crystal symmetry

The seven crystal systems are triclinic, monoclinic, orthorhombic, tetragonal, trigonal, hexagonal, and cubic system. Crystals can be diagrammatically represented by an orderly stacking of lattice cells, whose shape determines the crystal system to which they belong. Unit cells of identical shape can have lattice points, representing an atom or group of atoms, at their centers or faces, in addition to the corners. These additional lattice points further divide the seven crystal systems into 14 Bravais lattices, which are then subdivided into 32 crystal classes, or point groups. Each point group corresponds to a possible combination of rotations, reflections, inversions, and improper rotations. When translational elements are included, these point groups yield the 230 space groups [12].

A.2 In-library and Out-of-library Tasks

In-library identification is a fundamental task in crystallography that aims to accurately identify crystal types based on XRD patterns measured in various environments. Since 1938, crystallographers have been documenting all discovered structures and archiving them as Powder Diffraction Files (PDFs). By comparing and retrieving these PDFs, researchers can determine the structures of studied materials by matching them with historical data. With advancements in computing, numerous software programs have been developed to assist in the search-match process.

A related concept is out-of-library identification, which involves discovering previously unknown structures that lack any recorded information. This process relies on symmetry identification to determine the basic space group information and subsequent refinement processes. Traditionally, the crystal system to which a crystal belongs can be determined based on the crystal's physical properties, such as electrical conductivity, optical behavior, and thermal characteristics. Subsequently, the space group can be identified by examining extinction effects. This is followed by determining the ideal chemical formula according to the estimated number of atoms and Wyckoff positions. Validation is conducted through Rietveld refinement and site optimization, among other techniques.

We recommend two types of data splits:

- **In-library Classification:** This approach uses the default splitting in SimXRD. As shown in our benchmark, the dataset is split according to different simulation environments. Both training and testing datasets contain the same structures but under different simulation environments, corresponding to the in-library identification in XRD phase identification.
- **Out-of-library Classification:** We also recommend splitting the dataset according to crystal types. Both the training and testing datasets contain different structures, corresponding to the out-of-library identification in XRD phase identification. We provide the code for generating such splits based on SimXRD in the OutlibDataProcessor tool available [here](#).

A.3 Search-Match approach

Conventionally, the predominant method for in-library phase identification in X-ray powder diffraction patterns is the search-match approach, which comprises three main steps. Initially, (d, I) values, representing interplanar spacing (d) and intensity (I) of each peak, are extracted from the pattern. Subsequently, potential phases are sought from diffraction databases based on characteristic d values, such as Hanawalt indexes [61]. Following this, candidate phases are compared to the (d, I) values of the pattern using a scoring system to assess alignment, aiding in selecting the most suitable candidate phase. This process iterates until satisfactory alignment is achieved for most (d, I) values. A recent study [33] employs a distinct approach utilizing the Rietveld method for conducting a Full Profile Search-Match (FPSM). Crystal structures selected from databases are automatically aligned with raw data via the Rietveld method, culminating in a score determined by R_{wp} [38]. The phase with the highest score is acknowledged, and this iterative procedure persists until specified criteria are met. Subsequently, a Rietveld quantification is executed to ascertain the weight fraction of each phase. Despite advancements in computer technology enabling novel qualitative analysis methods, the core objective remains consistent: to match experimental data with database entries and calculate a corresponding score.

In-library query strategies, such as the search-match approach, can retrieve reference structures for subsequent refinement. These references are based on lattice geometry and include some information about atomic locations, thereby reducing the burden of subsequent optimization. However, this approach is ineffective for determining out-of-library structures. In contrast, using the space group helps determine the lattice structure, and subsequent optimization of atomic sites can be performed during the refinement process, which provides a general method for structural measurement practices.

A.4 XRD Pattern Simulation

Powder XRD offer a one-dimensional representation of the three-dimensional diffraction pattern and stand as the most common experimental measurement, as depicted in Figure 1. These patterns mirror the relative arrangement of atoms in real three-dimensional space. The interaction of X-rays with condensed materials during diffraction entails elastic collisions between photons and electrons. Therefore, conditions affecting atom arrangement and electron behavior influence the pattern shape.

The diffraction vector \mathbf{G}^* is defined as

$$|\mathbf{G}^*| = \frac{2 \sin \theta}{\lambda}, \quad (1)$$

where λ is the wavelength of the scattered particle and $\theta = 2\theta/2$, with 2θ being the angle between the incident and diffracted beams. In three dimensions, scattering occurs only at a discrete set of reciprocal vectors, \mathbf{K} , forming the reciprocal lattice,

$$\mathbf{K} = h\mathbf{a}^* + k\mathbf{b}^* + l\mathbf{c}^*, \quad (2)$$

where \mathbf{a}^* , \mathbf{b}^* , and \mathbf{c}^* are the reciprocal lattice vectors, and h , k , and l are constants. The diffraction condition is defined as

$$2\pi\mathbf{G}^* = \mathbf{K}. \quad (3)$$

The x-axis of simulation patterns d is the reciprocal of $|\mathbf{G}^*|$, i.e., $d = 1/|\mathbf{G}^*|$.

The diffraction intensity I^{WPEM} on each diffraction vector \mathbf{G}^* for a single phase is determined by

$$I^{WPEM}(\mathbf{G}^*) = SF_k^*F_k\varnothing LPOD + I^{BG}, \quad (4)$$

where S denotes the scale factor, F_k is the structure factor, F_k^* is the complex conjugate of F_k , \varnothing_k is the profile function, L_k is the Lorentz-polarization factor, P_k is the multiplicity, O_k is the preferred orientation factor, D_k is the Debye-Waller factor, and I^{BG} is the background intensity. The structure factor is computed as:

$$F_k = \sum_{j=1}^N f_j e^{2\pi i \mathbf{G}^* \cdot \mathbf{R}}, \quad (5)$$

where f_j is the form factor [18] in XRD, \mathbf{R} is the lattice coordinate of atom j , and N is the total number of atoms in a lattice cell. The profile function (\varnothing_k) is a Voigt function [2],

$$\varnothing_k = \frac{1}{\sigma\sqrt{2\pi}} \int_{-\infty}^{\infty} \left[\frac{\gamma}{(2\theta - t)^2 + \gamma^2} \right] \exp\left(-\frac{(2\theta - t)^2}{2\sigma^2}\right) dt, \quad (6)$$

where $\theta = \arcsin\left(\frac{\lambda|\mathbf{G}^*|}{2}\right)$. Peak broadening is correlated with the Full Width at Half Maximum (FWHM, Γ), where $2\gamma = 2\sqrt{2\ln 2}\sigma = \Gamma$ [3]. Γ is calculated by Scherrer's equation [39] related to finite grain size.

The Lorentz-polarization L_k is calculated by,

$$L_k = \frac{1 + \cos^2 2\theta}{\sin^2 \theta \cos \theta}. \quad (7)$$

The multiplicity P_k is determined by counting the number of diffraction vectors present within an Ewald diffraction sphere. The Debye-Waller factor D_k is calculated by ,

$$D_k = e^{-2M}, \quad (8)$$

where $M = \frac{6h^2T}{mk\Theta^2} \left(\varnothing\left(\frac{\Theta}{T}\right) + \frac{\Theta}{4T}\right) (\sin^2 \theta) / \lambda$, h is Planck's constant, m is atom mass, k is Boltzmann constant, Θ is the average characteristic temperature, T is absolute temperature, and $\varnothing(\Theta/T)$ is the Debye function. The diffraction pattern, expressed as a function of d , is independent of λ .

The state of the specimen is simulated by:

- Finite grain size: the average grain size is set as a random number in the range of 2 nm to 50 nm to replicate the degree of experimental broadening [36]. Instrumental broadening becomes apparent in the experimental patterns as convolution with the crystal peak occurs. Typically, in the refinement process, it is common to separate observed peaks into Voigt and instrumental components. However, quantifying the instrumental component proves challenging as it varies with the diffraction angle. Therefore, in our simulations, we opt for a smaller grain size than realistic to accurately replicate the degree of experimental broadening.
- Orientation: the ideal powder specimen is assumed to have no orientation, however, this is impossible. The orientation effect arises from the uneven distribution of small grains in the incident beam, leading to an uneven distribution of reciprocal sites across the reciprocal spheres of the powder specimen. To simulate the impact of orientation, we set the intensity by perturbation within a 40% range based on the ideal simulation to mimic the orientation randomness.
- Thermal vibration: the temperature is converted to the kinetic energy of atoms, which is simulated by allowing atoms to shift from their average positions within a range of 0.01-0.5 angstrom.
- Internal stress: internal stress is simulated by applying elastic deformation of the recorded lattice constant by up to 10%.
- Instrument zero shifting: the zero shift is simulated by randomly translating 2θ within -1.2 to 1.2 degrees.
- Instrument noise: 2% Gaussian white noise is added to the entire pattern to reflect instrument noise.
- Inelastic Scattering: A sixth-order polynomial function is employed to simulate the background distribution, encompassing phenomena such as Compton scattering, fluorescence, and multiple scattering. This simulated background is then integrated into the XRD pattern with a 2% ratio.

A.5 Crystal and diffraction

Among various investigative methods, diffraction analysis stands out as exceptionally potent for probing microstructure, primarily due to its sensitivity to atomic arrangement and the element specificity of atom scattering power. Each intensity maximum, termed a line profile or peak, within a diffraction pattern reflects the atomic arrangement along certain direction of the diffracting material, as depicted in Figure 6.

Powder X-ray diffraction, in particular, furnishes a remarkably diverse array of structural details, encoded in the material- and instrument-specific distribution of coherently scattered monochromatic wave intensity, with wavelengths corresponding to lattice spacing. The X-rays are generated by a cathode ray tube, filtered to produce monochromatic radiation, collimated for concentration, and directed towards the sample. When conditions satisfy Bragg's Law, which relates the wavelength of electromagnetic radiation to the diffraction angle and lattice spacing in a crystalline sample, the incident rays interact with the sample to produce constructive interference and a diffracted ray.

The diffracted X-rays are subsequently detected, processed, and quantified. By scanning the sample across a range of diffraction angles, all possible diffraction directions of the lattice are accessible due to the random orientation of powdered material.

Conversion of diffraction peaks to d-spacings facilitates mineral identification, since each mineral possesses a unique set of d-spacings. This identification is typically accomplished through comparison with standard reference patterns.

A.6 Symmetry recognition in structure determination

Pattern refinement [46, 47] is essential for accurately determining the crystal structure in diffraction practices. In XRD refinement, the critical initial step involves identifying the crystalline phase of the given pattern. This phase identification is crucial as it facilitates the calculation of the static structure factor [56], which aids in determining atom sites during refinement. The primary step in refinement

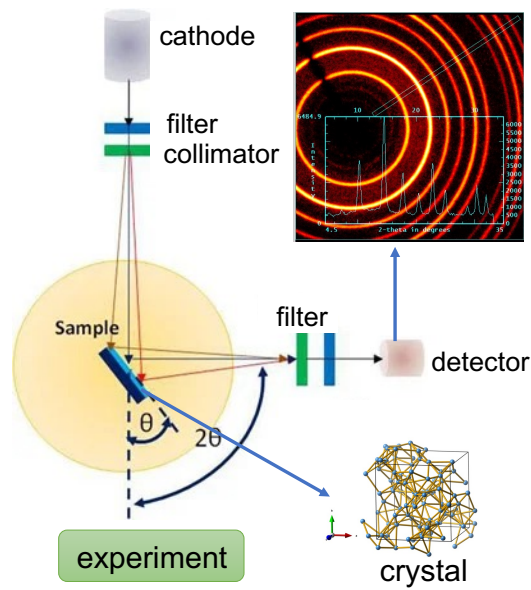


Figure 6: Experimental procedure for recording XRD patterns.

is establishing the geometry of the crystal lattice cell by solving the diffraction indices corresponding to a set of lattice planes for each diffraction peak, a process known as indexing calculation [49].

Utilizing existing crystal databases, the commonly employed search-match approach retrieves potential structures that match the observed pattern, essentially performing in-library identification. The matched structure, along with basic crystallographic information, including crystal symmetry, serves as a foundational element for further analysis.

Whether the observed patterns are from in-library or out-of-library crystals, symmetry identification combined with indexing is a generic method for determining lattice geometry to initiate the refinement process. This is why many researchers in materials science and physics pursue a general method to derive the symmetry of structures based on diffraction patterns. Once the fundamental crystallographic information is acquired, techniques such as pattern decomposition and Rietveld refinement [46, 47, 24] come into play. These methodologies facilitate the determination of atom sites, temperature factors, grain sizes, residual stress, and other intricate structural details from the diffraction patterns on a case-by-case basis, thereby contributing to the comprehensive elucidation of a crystal structure.

A.7 Whole Powder Pattern Fitting and Refinement

Structure refinement is an effective method for determining crystal structures. Traditionally, refinement begins with a set of reasonably estimated parameters with physical significance. Accurately identifying the structure's space group aids in establishing rational parameters. However, without prior structural knowledge, this process becomes trial and error. Although identifying the space group initiates the process, its validation relies on refinement outcomes.

A significant advancement in powder diffraction fitting for structure refinement emerged with the Rietveld method[46, 47], which pioneered whole pattern fitting over the analysis of individual, non-overlapping Bragg diffraction peaks. The Whole Powder Pattern Fitting (WPPF) approach within the Rietveld method uses profile intensity calculations and a least-squares algorithm for structure refinement. By minimizing the disparities between observed experimental profiles and theoretical profiles, it extracts all structural information. Once fitting reaches its limit, the parameters in the theoretical model represent the only determinable physical information. SimXRD's pattern simulation also relies on the structural information contained within the theoretical model. The Pawley[44] and Le Bail[25] methods, two widely used WPPF techniques, are developed after the Rietveld method.

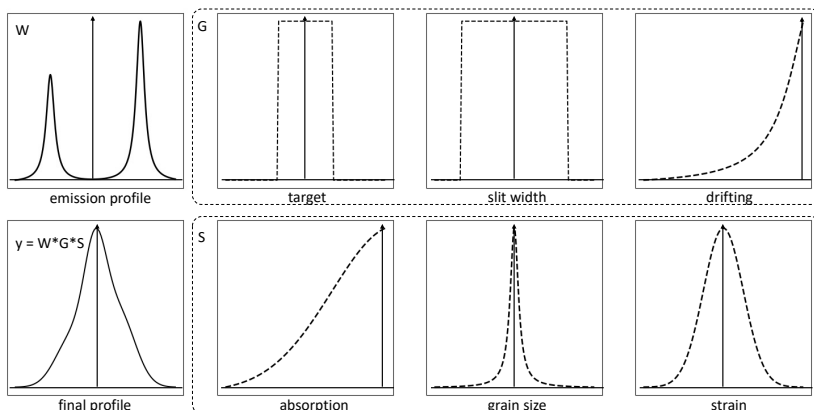


Figure 7: The emission (W), instrumental factor (G), and the tested specimen (S) are convoluted to form the diffraction peak.

These parameters with physical significance are diverse, and one important type is peak shape parameters. The parameters of each diffraction peak (positions, intensities, and shapes) within a whole XRD pattern offer detailed structural insights from different aspects, making their quantitative and accurate extraction from the overall XRD profile highly significant. This quantification of peak information and the subsequent derivation of physical parameters constitute the essence of the refinement endeavor.

Numerous factors influence diffraction peak shapes, creating a multiphysical coupling effect (see Figure 7). The full pattern fitting in the commercial TOPAS package[13], also known as the fundamental parameters approach, employs a convolution function to describe peak shapes, as illustrated by the equation:

$$y(x) = [W(x) * G(x)] * S(x) \quad (9)$$

where $*$ denotes the convolution process, and $W(x)$, $G(x)$, and $S(x)$ represent contributions to the observed XRD pattern from the emission source, instrumental factors, and the tested specimen, respectively.

The simulation process of SimXRD considers the multiphysical coupling process to generate a wide range of diffraction patterns.

A.8 Dataset Card

Motivation

1. **For what purpose was the dataset created? Was there a specific task in mind? Was there a specific gap that needed to be filled?** Please provide a description.
 - The dataset addresses a fundamental task in crystallography: identifying crystal types by analyzing XRD patterns. Traditional methods involve a time-consuming search-match process through known diffraction patterns. Recent studies have advanced this by training neural networks on simulated XRD datasets to classify patterns by specific symmetries, though these often focus on specific materials. To improve generalization, models need comprehensive coverage of structures and alignment with experimental patterns under various conditions. Creating such high-fidelity simulated datasets is challenging due to the complex simulation processes involved. SimXRD-4M was developed to overcome these challenges and fill this gap.
2. **Who created the dataset (e.g., which team, research group) and on behalf of which entity (e.g., company, institution, organization)?**
 - The authors created the dataset.
3. **Who funded the creation of the dataset? If there is an associated grant, please provide the name of the grantor and the grant name and number.**

- N/A

4. **Any other comments?**

- No.

Composition

1. **What do the instances that comprise the dataset represent (e.g., documents, photos, people, countries)? Are there multiple types of instances (e.g., movies, users, and ratings; people and interactions between them; nodes and edges)?** Please provide a description.

- Each row in the SimXRD dataset represents a diffraction pattern, consisting of 3051 pairs of values representing lattice plane distance (d) and diffraction intensity (I). Additionally, each instance includes information such as chemical formula (string), atomic elements (list), space group (integer), and crystal system (integer).

2. **How many instances are there in total (of each type, if appropriate)?**

- SimXRD-4M consists of 4,065,346 simulated powder X-ray diffraction patterns

3. **Does the dataset contain all possible instances or is it a sample (not necessarily random) of instances from a larger set?** If the dataset is a sample, then what is the larger set? Is the sample representative of the larger set (e.g., geographic coverage)? If so, please describe how this representativeness was validated/verified. If it is not representative of the larger set, please describe why not (e.g., to cover a more diverse range of instances, because instances were withheld or unavailable).

- SimXRD-4M does not contain all possible instances of XRD patterns. However, it covers all the crystals contained in the latest Material Project [20] (almost all inorganic crystals), denoted as MP-2024.1. The diffraction pattern for a given crystal varies depending on various physical settings. We provided 33 coupling conditions for diffraction. Since many physical settings affecting diffraction patterns are continuous values, it is impossible to provide all real situations. The specific settings are determined based on our domain knowledge and experience in XRD practice.

4. **What data does each instance consist of? “Raw” data (e.g., unprocessed text or images) or features?** In either case, please provide a description.

- The each instance includes:
- `element`: A list of chemical symbols representing the elements in the crystal (e.g., ['S', 'Pb', 'O']).
- `latt_dis`: A list of lattice plane distances.
- `intensity`: A list of diffraction intensities.
- `spg`: An integer representing the space group number.
- `crystal_system`: An integer representing the crystal system number.

5. **Is there a label or target associated with each instance? If so, please provide a description.**

- SimXRD has clearly categorized labels of crystal systems (integers, 1-7) and space groups (integers, 1-230).

6. **Is any information missing from individual instances? If so, please provide a description explaining why this information is missing (e.g. because it was unavailable).** This does not include intentionally removed information but might include, e.g., redacted text.

- No.

7. **Are relationships between individual instances made explicit (e.g., users’ movie ratings, social network links)? If so, please describe how these relationships are made explicit.**

- No.

8. **Are there recommended data splits (e.g., training, development/validation, testing)? If so, please provide a description of these splits, explaining the rationale behind them.**

- No.

9. **Are there any errors, sources of noise, or redundancies in the dataset? If so, please provide a description.**
 - No.
10. **Is the dataset self-contained, or does it link to or otherwise rely on external resources (e.g., websites, tweets, other datasets)?** If it links to or relies on external resources, a) are there guarantees that they will exist and remain constant over time; b) are there official archival versions of the complete dataset (i.e., including the external resources as they existed at the time the dataset was created); c) are there any restrictions (e.g., licenses, fees) associated with any of the external resources that might apply to a dataset consumer? Please provide descriptions of all external resources and any restrictions associated with them, as well as links or other access points, as appropriate.
 - SimXRD relies on the crystal database. Currently, it contains all the recorded data in the Material Project (MP) crystal database. The MP database is open-sourced. Further development of SimXRD may require supplementing new crystal structures after a certain period when significant new crystals are added to the MP database.
11. **Does the dataset contain data that might be considered confidential (e.g., data that is protected by legal privilege or by doctor– patient confidentiality, data that includes the content of individuals’ non-public communications)?** If so, please provide a description.
 - No, there are no confidential datapoints in SimXRD.
12. **Does the dataset contain data that, if viewed directly, might be offensive, insulting, threatening, or might otherwise cause anxiety?** If so, please describe why.
 - No.
13. **Does the dataset identify any subpopulations (e.g., by age, gender)?** If so, please describe how these subpopulations are identified and provide a description of their respective distributions within the dataset.
 - No.
14. **Is it possible to identify individuals (i.e., one or more natural persons), either directly or indirectly (i.e., in combination with other data) from the dataset? If so, please describe how.**
 - No.
15. **Does the dataset contain data that might be considered sensitive in any way (e.g., data that reveals race or ethnic origins, sexual orientations, religious beliefs, political opinions or union memberships, or locations; financial or health data; biometric or genetic data; forms of government identification, such as social security numbers; criminal history)?** If so, please provide a description.
 - No.
16. **Any other comments?**
 - No.

Collection Process

1. **How was the data associated with each instance acquired?** Was the data directly observable (e.g., raw text, movie ratings), reported by subjects (e.g., survey responses), or indirectly inferred/derived from other data (e.g., part-of-speech tags, model-based guesses for age or language)? If data was reported by subjects or indirectly inferred/derived from other data, was the data validated/verified? If so, please describe how.
 - The crystal structures in this study were sourced from the Materials Project database. We used the latest dataset, MP-2024.1, containing 154,718 structures as of January 2024. To ensure data quality, we used Spglib to check for consistency in space group numbers and atomic arrangements, excluding structures with broken symmetry, duplication, or discrepancies. We retained only structures with up to 500 atoms per lattice cell, covering nearly all inorganic materials, resulting in 119,569 screened structures. The XRD patterns, influenced by the crystal’s structure and practical factors like specimen state and instrumental parameters, were simulated using custom software WPEM.

2. **what mechanisms or procedures were used to collect the data (e.g., hardware apparatus or sensor, manual human curation, software program, software API)?**How were these mechanisms or procedures validated?
 - The crystal database [MP](#) and screening package [Spplib](#) are open-sourced. The simulation software is [WPEM](#), homemade and not completely open-sourced yet, but its effectiveness has been recognized by multiple peer researches in material and physical communities[29, 6, 54, 45, 16]. Additionally, the details of the simulation process are provided in mathematics in Appendix A.4.
3. **Over what timeframe was the data collected? Does this timeframe match the creation timeframe of the data associated with the instances (e.g., recent crawl of old news articles)?**If not, please describe the timeframe in which the data associated with the instances was created.
 - Crystal data recorded in the MP database up to January 2024 were retrieved. The simulated data were generated between January and May 2024.
4. **Were any ethical review processes conducted (e.g., by an institutional review board)?**If so, please provide a description of these review processes, including the outcomes, as well as a link or other access point to any supporting documentation.
 - No ethical problems were involved.
5. **Did you collect the data from the individuals in question directly, or obtain it via third parties or other sources (e.g., websites)?**
 - The crystal database [MP](#) is open for acquisition.
6. **Did the individuals in question consent to the collection and use of their data?**If so, please describe (or show with screenshots or other information) how consent was requested and provided, and provide a link or other access point to, or otherwise reproduce, the exact language to which the individuals consented.
 - Not applicable.
7. **If consent was obtained, were the consenting individuals provided with a mechanism to revoke their consent in the future or for certain uses?**If so, please provide a description, as well as a link or other access point to the mechanism (if appropriate).
 - Not applicable.

Preprocessing/cleaning/labeling

1. **Was any preprocessing/cleaning/labeling of the data done (e.g., discretization or bucketing, tokenization, part-of-speech tagging, SIFT feature extraction, removal of instances, processing of missing values)?**If so, please provide a description. If not, you may skip the remainder of the questions in this section.
 - All spectrum data contained in SimXRD provide full information with XRD features and labels. We did not perform any further preprocessing of the data.
2. **Is the software used to preprocess/clean/label the instances available?**If so, please provide a link or other access point.
 - We provide a data loader associated with our dataset as [dataloader](#).

Uses

1. **Has the dataset been used for any tasks already?**If so, please provide a description.
 - Not yet. We offer benchmarks to illustrate its potential in library space group and crystal system classification tasks, as illustrated in the section : Use Cases of SimXRD Dataset.
2. **Is there a repository that links to any or all papers or systems that use the dataset?**If so, please provide a link or other access point.
 - Please refer to [SimXRD-4M](#).

3. **Is there anything about the composition of the dataset or the way it was collected and preprocessed/cleaned/labeled that might impact future uses?** For example, is there anything that a future user might need to know to avoid uses that could result in unfair treatment of individuals or groups (e.g., stereotyping, quality of service issues) or other undesirable harms (e.g., financial harms, legal risks) If so, please provide a description. Is there anything a future user could do to mitigate these undesirable harms?
 - Not applicable.

Distribution

1. **Will the dataset be distributed to third parties outside of the entity (e.g., company, institution, organization) on behalf of which the dataset was created?** If so, please provide a description.
 - Yes, the dataset will be open-source.
2. **How will the dataset be distributed (e.g., tarball on website, API, GitHub)?** Does the dataset have a digital object identifier (DOI)?
 - The dataset can be acquired from the website [SimXRD-4M](#).
3. **When will the dataset be distributed?**
 - Starting from June 1, 2024.
4. **Will the dataset be distributed under a copyright or other intellectual property (IP) license, and/or under applicable terms of use (ToU)?** If so, please describe this license and/or ToU, and provide a link or other access point to, or otherwise reproduce, any relevant licensing terms or ToU, as well as any fees associated with these restrictions.
 - CC-BY-4.0
5. **Will the dataset be distributed under a copyright or other intellectual property (IP) license, and/or under applicable terms of use (ToU)?** If so, please describe this license and/or ToU, and provide a link or other access point to, or otherwise reproduce, any relevant licensing terms or ToU, as well as any fees associated with these restrictions.
 - No.
6. **Have any third parties imposed IP-based or other restrictions on the data associated with the instances?** If so, please describe these restrictions, and provide a link or other access point to, or otherwise reproduce, any relevant licensing terms, as well as any fees associated with these restrictions.
 - No.
7. **Do any export controls or other regulatory restrictions apply to the dataset or to individual instances?** If so, please describe these restrictions, and provide a link or other access point to, or otherwise reproduce, any supporting documentation.
 - No, the dataset is open for any application.

Maintenance

1. **Who will be supporting/hosting/maintaining the dataset?**
 - [SimXRD-4M](#) will host the dataset and we will maintain the dataset.
2. **How can the owner/curator/manager of the dataset be contacted (e.g., email address)?**
 - The authors can be contacted via bca0686@connect.hkust-gz.edu.cn
3. **Is there an erratum?** If so, please provide a link or other access point.
 - No
4. **Will the dataset be updated (e.g., to correct labeling errors, add new instances, delete instances)?** If so, please describe how often, by whom, and how updates will be communicated to users (e.g., mailing list, GitHub)?
 - There are no older versions of [SimXRD-4M](#).

- If any updates are necessary in future development, we will provide essential updates and communicate all revisions and changes through the database website [SimXRD-4M](#). We will provide the updated version and maintain a history of versions.
5. **If the dataset relates to people, are there applicable limits on the retention of the data associated with the instances (e.g., were individuals in question told that their data would be retained for a fixed period of time and then deleted)?** If so, please describe these limits and explain how they will be enforced.
 - Not applicable.
 6. **Will older versions of the dataset continue to be supported/hosted/maintained?** If so, please describe how. If not, please describe how its obsolescence will be communicated to users.
 - There are no older versions of SimXRD-4M.
 - If any updates are necessary in future development, all older versions of the dataset will continue to be supported/hosted/maintained. The database website [SimXRD-4M](#) will record all historical datasets and the newest dataset versions along with commit histories.
 7. **If others want to extend/augment/build on/contribute to the dataset, is there a mechanism for them to do so?** If so, please provide a description. Will these contributions be validated/verified? If so, please describe how. If not, why not? Is there a process for communicating/distributing these contributions to other users? If so, please provide a description.
 - Yes, we accept user contributions to extend/augment/build on/contribute to the dataset. If any user wishes to contribute, they need to provide crystal data and simulation software for strict screening by us to ensure data quality. The application can be launched by submitting a pull request on our dataset GitHub repository [SimXRDDataset](#) or by contacting the author directly for data merging.

Croissant metadata

1. **URL to Croissant metadata record documenting the dataset/benchmark available for viewing and downloading by the reviewers.** You can create your Croissant metadata using e.g. the Python library available here: <https://github.com/mlcommons/croissant>.
 - A sample dataset is available for viewing and downloading, hosted by Hugging Face Datasets: [SimXRDreview](#).
 - The sample dataset contains 5,000 training patterns, 1,000 validation patterns and 2,000 test patterns.
 - The code to access the dataset metadata is provided below:

```
1 pip install mlcroissant
```

```
1 import mlcroissant as mlc
2
3 url = "https://huggingface.co/datasets/caobin/SimXRDreview/raw
4 /main/simxrd_croissant.json"
5 dataset_info = mlc.Dataset(url).metadata.to_json()
6 print(dataset_info)
```

Listing 1: Example Python code